


<b>Search Notes</b> 	<b>Application/Control No.</b> 10636076	<b>Applicant(s)/Patent Under Reexamination</b> LIN ET AL.
	<b>Examiner</b> Chawan, Sheela C	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	145	7/28/07	SCC
118	719	"	"
219	121.41	"	"
414	935	"	"
ABOVE SEARCH UP-DATE.		"	"

SEARCH NOTES			
Search Notes		Date	Examiner
SEARCH EAST AND OTHER DATABASE , SEE ATTACHED SEARCH HISTORY.		7/28/07	SCC
382/145.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.		"	"
118/719,715,728,729,712.CCLS.		"	"
" "		"	"
219/121.43, 121.41.CCLS.		"	"
" "		"	"
414/936,939,217, 935,937.CCLS.		"	"
" "		"	"
ABOVE SEARCH UP-DATE.		"	"
INVENTOR NAME SEARCH.		"	"
IEEE OR INSPEC SEARCH.		"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	145	7/28/07	SCC
118	719	"	"
219	121.41	"	"
414	935	"	"